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(54) **CIRCUIT FOR MULTI-PATH INTERFERENCE MITIGATION IN AN OPTICAL COMMUNICATION SYSTEM**

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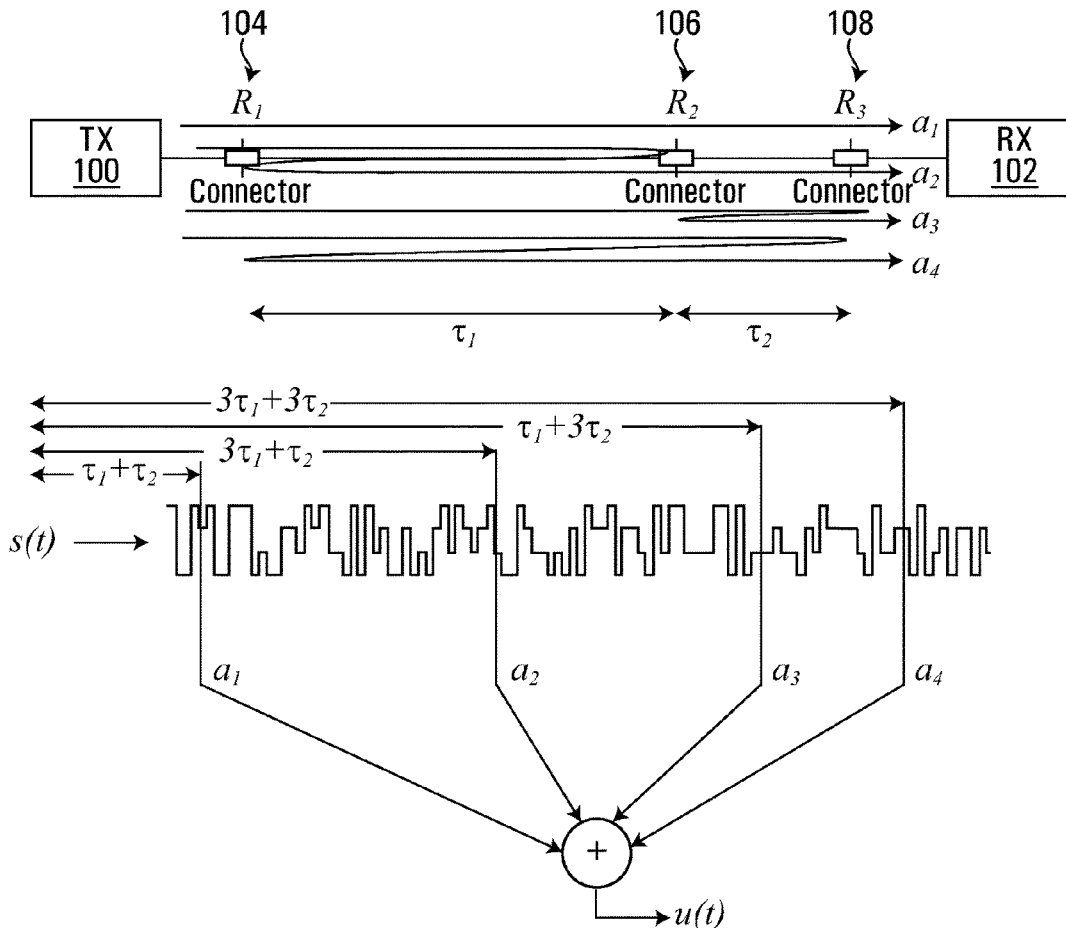
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(63) Continuation of application No. 16/790,463, filed on Feb. 13, 2020, now Pat. No. 10,880,015, which is a continuation of application No. 16/259,760, filed on Jan. 28, 2019, now Pat. No. 10,601,518, which is a continuation of application No. 15/836,603, filed on Dec. 8, 2017, now Pat. No. 10,236,994, which is a continuation of application No. 15/040,812, filed on Feb. 10, 2016, now Pat. No. 9,876,581.

(57) **ABSTRACT**

A circuit and method for mitigating multi-path interference in direct detection optical systems is provided. Samples of an optical signal having a pulse amplitude modulated (PAM) E-field are processed by generating a PAM level for each sample. For each sample, the sample is subtracted from the respective PAM level to generate a corresponding error sample. The error samples are lowpass filtered to produce estimates of multi-path interference (MPI). For each sample, one of the estimates of MPI is combined with the sample to produce an interference-mitigated sample.



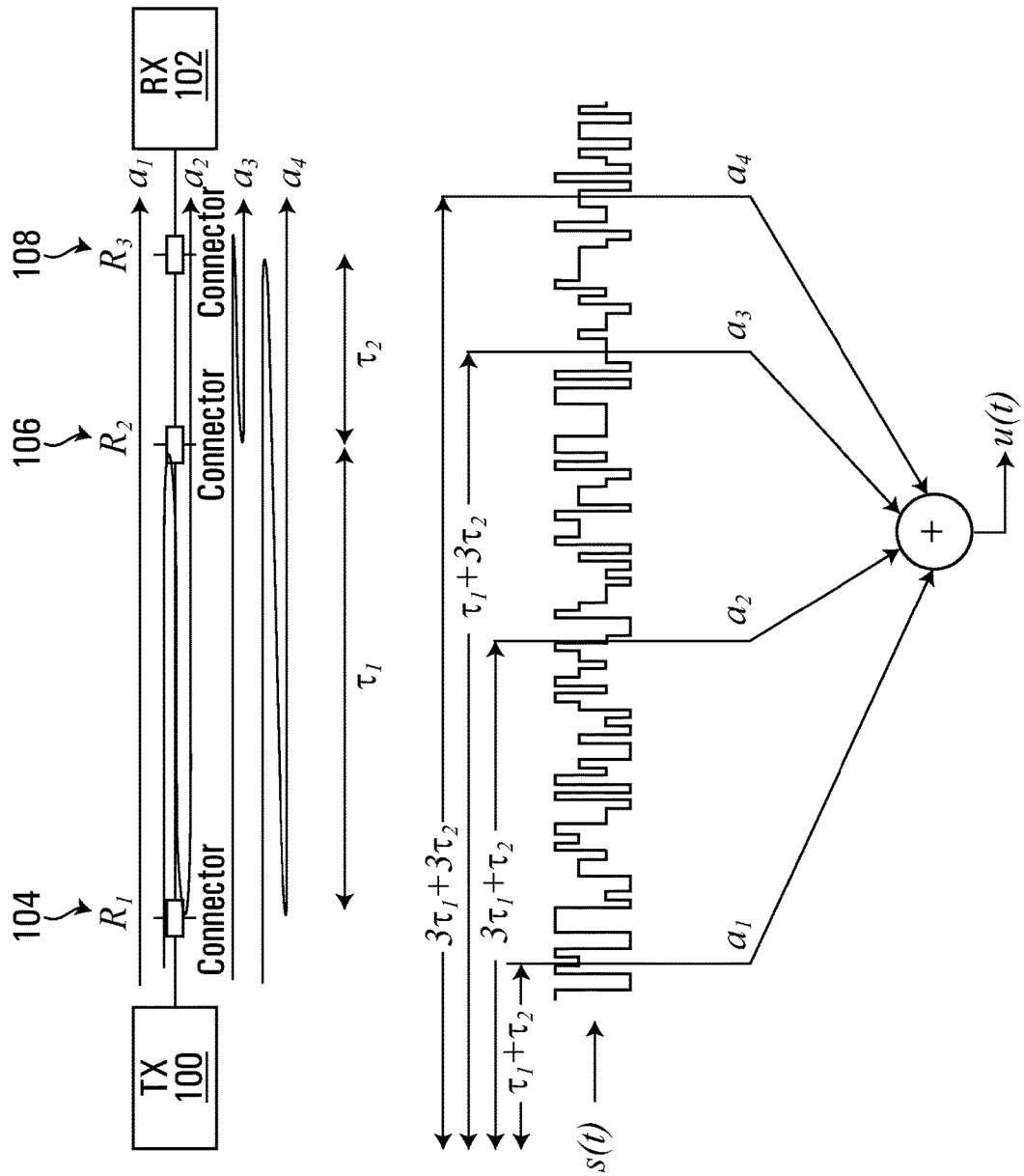


FIG. 1

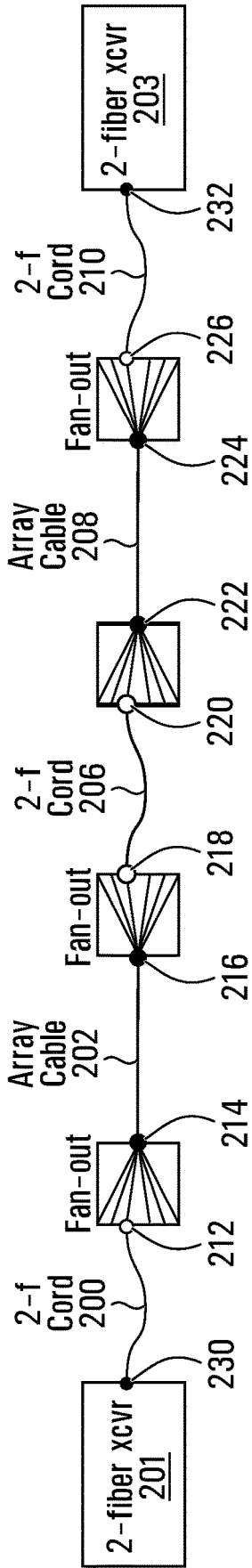


FIG. 2

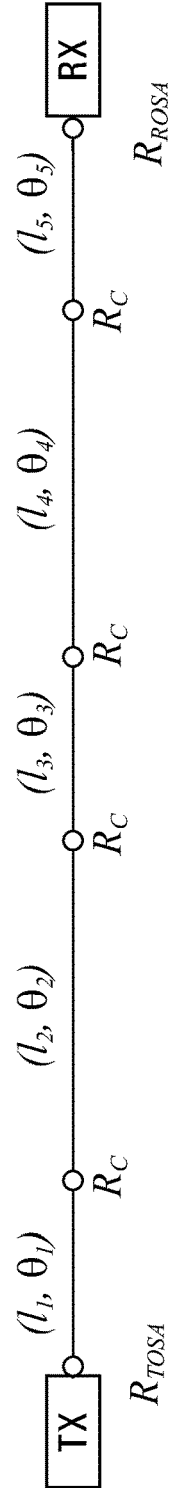


FIG. 3

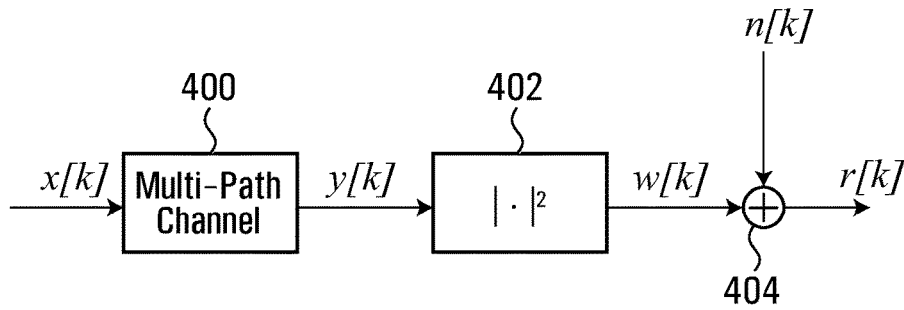


FIG. 4

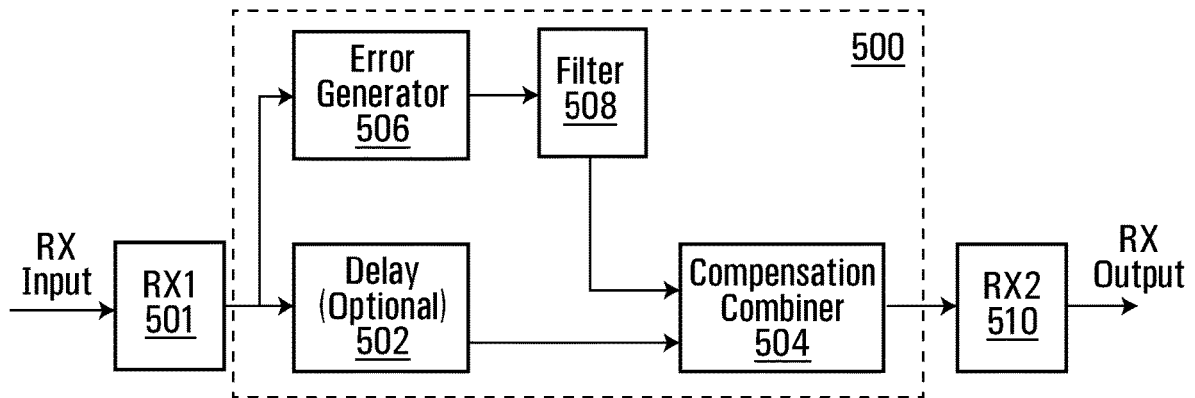


FIG. 5A

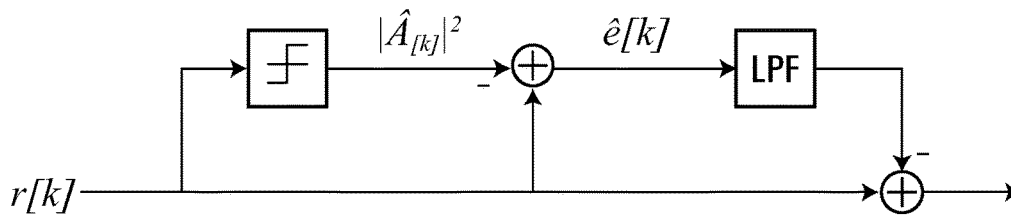


FIG. 5B

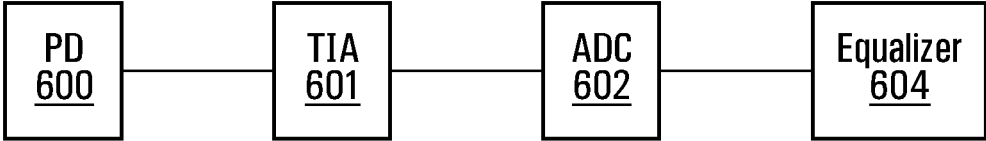


FIG. 6

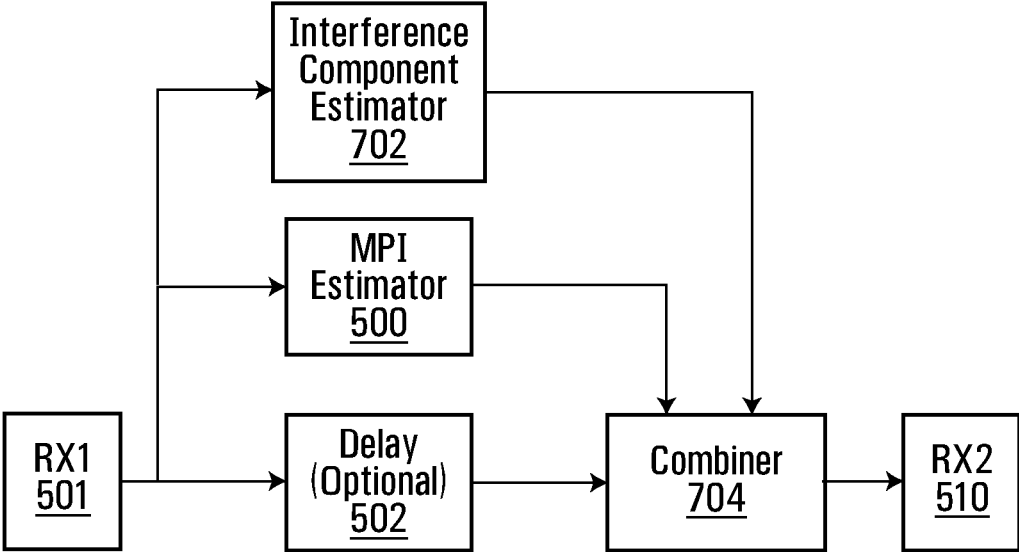


FIG. 7

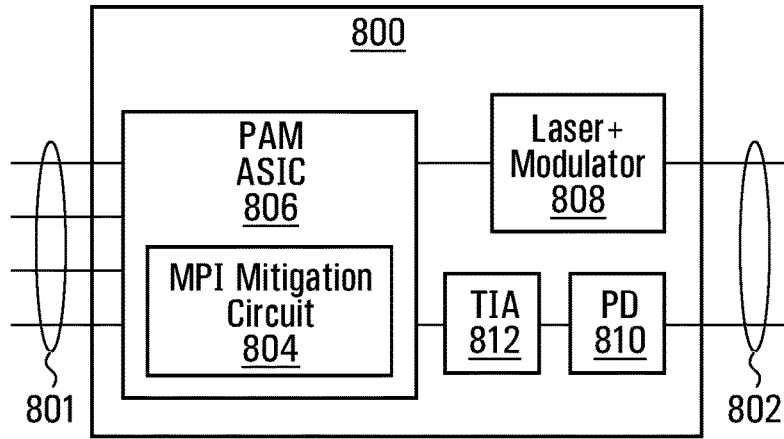


FIG. 8

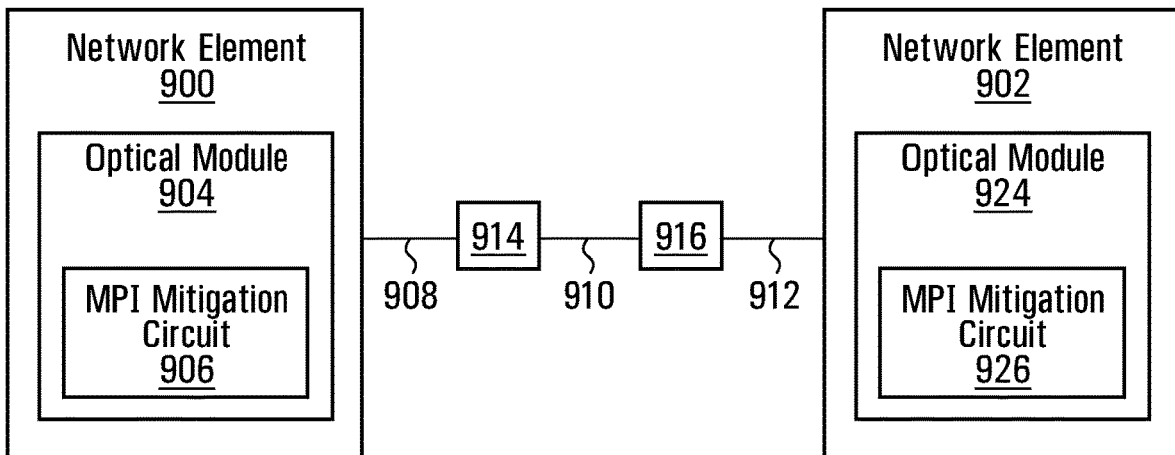


FIG. 9

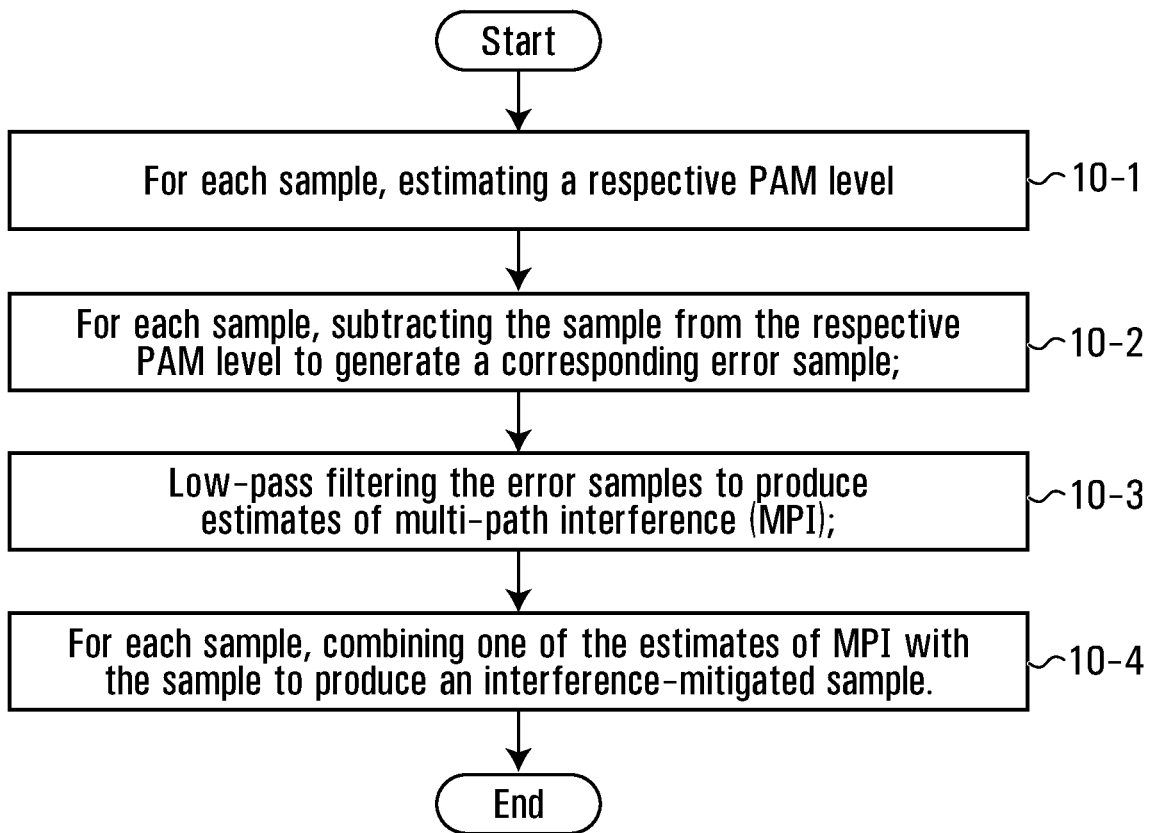


FIG. 10

**CIRCUIT FOR MULTI-PATH
INTERFERENCE MITIGATION IN AN
OPTICAL COMMUNICATION SYSTEM**

CROSS-REFERENCE

[0001] The present application is a continuation of U.S. application Ser. No. 16/790,463 filed Feb. 13, 2020, which is a continuation of U.S. application Ser. No. 16/259,760 filed Jan. 28, 2019, now U.S. patent Ser. No. 10/601,518 issued Mar. 24, 2020, which is a continuation of U.S. application Ser. No. 15/836,603 filed Dec. 8, 2017, now U.S. Pat. No. 10,236,994 issued Mar. 19, 2019, which is a continuation of U.S. application Ser. No. 15/040,812 filed Feb. 10, 2016, now U.S. Pat. No. 9,876,581 issued Jan. 23, 2018, the contents of which are incorporated by reference herein in the entirety.

FIELD

[0002] The application relates to systems and methods for mitigating interference in an optical communications system.

BACKGROUND

[0003] In a direct-detected optical communications system, multi-path interference (MPI) originates from combinations of reflections of a transmitted waveform at optical interfaces (connectors, receiver/transmitter interfaces). An example is depicted in FIG. 1 which shows a transmitter **100** connected to a receiver **102** over a sequence of optical cables connected at optical interfaces **104, 106, 108**. After transmission of a signal $s(t)$ by transmitter **100**, due to reflections at the interfaces **104, 106, 108**, a signal $u(t)$ received at receiver **102** is the sum of a set of delayed replicas of a transmitted signal. Generally indicated at **110** is a logically equivalent version of the system of FIG. 1 showing the summing of four delayed components, with respective attenuations a_1, a_2, a_3, a_4 .

[0004] Another source of the interference is due to reflections that occur in the electrical domain, for example after a photodiode in the receiver, or prior to a laser modulator in the transmitter. These electrical reflections can be cancelled directly, by estimating the delay and amplitude of each component. Such electrical reflections typically occur over very short distances (on the order of tens of mm or less), so they remain within a small number of bauds from the main signal.

BRIEF DESCRIPTION OF THE DRAWINGS

[0005] Embodiments of the disclosure will now be described with reference to the attached drawings in which:

[0006] FIG. 1 depicts an optical system and corresponding signal with multi-path interference;

[0007] FIG. 2 is another example of an optical system having connectors with differing return losses;

[0008] FIG. 3 is a multi-path channel model for the optical system of FIG. 2

[0009] FIG. 4 is a block diagram of a baud rate system model;

[0010] FIG. 5A is a block diagram of an optical receiver having a MPI mitigation circuit;

[0011] FIG. 5B is a baud rate model of the receiver of FIG. 5A;

[0012] FIG. 6 is a block diagram of an example implementation of the RX1 component of FIG. 5A;

[0013] FIG. 7 is a block diagram of an optical receiver having a MPI mitigation circuit and interference component estimator;

[0014] FIG. 8 is a block diagram of an optical module having an MPI mitigation circuit;

[0015] FIG. 9 is a block diagram of an optical network including network elements with MPI mitigation circuits; and

[0016] FIG. 10 is a flowchart of a method of performing MPI mitigation.

DETAILED DESCRIPTION

[0017] As mentioned in the background section, interference due to reflections that occur in the electrical domain can be cancelled directly, by estimating the delay and amplitude of each component, because the electrical reflections typically occur over very short distances (~mm), so they remain within a small number of bauds from the main signal. Traditional approaches to interference cancellation explicitly cancel the individually reflected terms (for example using a decision-feedback equalizer). This approach is challenging to apply to MPI, since the reflections may be delayed by many 1000s of bauds, and the size and location of the taps may vary as a function of time, for example due to mechanical vibrations and laser phase variation. It is very challenging to make the adaptation loops sufficiently fast, and a large amount of memory is required to store past decisions.

[0018] In addition, the impact of MPI is level-dependent for direct-detection receivers, i.e., a receiver that detects power of optical waveform. More specifically, in a multi-level modulation schemes such as pulse amplitude modulation (PAM), the effect of MPI is larger for larger PAM levels than for smaller PAM levels.

[0019] According to one aspect of the present invention, there is provided a method of processing a plurality of samples of an optical signal having a pulse amplitude modulated (PAM) E-field, the method comprising: for each sample, estimating a respective PAM level; for each sample, subtracting the sample from the respective PAM level to generate a corresponding error sample; low-pass filtering the error samples to produce estimates of multi-path interference (MPI); for each sample, combining one of the estimates of MPI with the sample to produce an interference-mitigated sample.

[0020] According to another aspect of the present invention, there is provided a circuit for processing a plurality of samples of an optical signal having a pulse amplitude modulated (PAM) E-field, the circuit comprising: a slicer that, for each sample, estimates a respective PAM level of the sample; a subtractor that, for each sample, subtracts the sample from the respective PAM level to generate a corresponding error sample; a low-pass filter that filters the error samples to produce estimates of multi-path interference (MPI); a combiner that for each sample, combines one of the estimates of MPI with the sample to produce an interference-mitigated sample.

[0021] An example of an optical communications system is depicted in FIG. 2. This example includes a first transceiver **201** having a transmit optical subassembly (TOSA) connector **230** and a second transceiver **204** having a receive optical subassembly (ROSA) connector **232**. The two trans-

ceivers **201,204** are connected by an optical path having five sections of cable **200,202,206,208,210**, and connectors **212, 214,216,218,220,222,224,226**. In a typical optical communications systems, there will be connectors having different qualities. In FIG. 2, the connectors **214,216,222,224** have excellent return loss compared to the other connectors. The system can be modelled using a multi-path channel model such as depicted in FIG. 3 where the connectors with excellent return loss have been abstracted out as they do not make a significant contribution to MPI. For this specific example, the five physical lengths of cabling having lengths l_j . The model includes interfaces at the four relatively poorer return loss connectors plus at the TOSA connector and the ROSA connector. It should be understood that the approach generalizes to an arbitrary number of connectors and cables.

[0022] Each connector has an associated return loss. Each length of cable has an associated phase shift θ_j which relates to link-induced phase randomization (relative to main signal, also referred to herein as the interference victim, or simply victim) of interferers.

[0023] A baud rate system model based on the system of FIG. 2 (but again, more generally upon a system with any number of connectors and cables) is depicted in FIG. 4. In this model, an input sample $x[k]$ is transmitted over a multi-path channel which transforms the input sample $x[k]$ into $y[k]$. Direct detection upon $y[k]$ is performed at **402** to produce $w[k]$. A noise contribution $n[k]$ is added at **404** to produce a received sample $r[k]$. The complex baseband representation of the input sample $x[k]$ can be modelled according to:

$$x[k]=A[k]e^{j\phi[k]}$$

[0024] Where $A[k]$ is the PAM level for the input sample $x[k]$, and is one of a set of PAM levels according to the PAM modulation scheme and $\phi[k]$ is the phase for input sample $x[k]$.

[0025] In addition, $y[k]$, $r[k]$, and the MPI interference component can be modelled according to:

$$y[k]=A[k]e^{j(\phi[k]+\sum_{m=0}^M\theta_m)}+\sum_m\gamma_m A[k-d_m]e^{j(\phi[k-d_m]+\sum_{m=0}^M\theta_m+\phi)}$$

$$r[k]=A[k]e^{j(\phi[k]+\sum_{m=0}^M\theta_m)}+\sum_m\gamma_m A[k-d_m]e^{j(\phi[k-d_m]+\sum_{m=0}^M\theta_m+\phi)}+n[k]$$

$$\text{MPI Interference: } 2|A[k]|\sum_m\gamma_m A[k-d_m] \cos(\phi[k]-\phi[k-d_m]+\psi[m])$$

[0026] For the purpose of this model, it is assumed that:

[0027] the phase of the transmitted signal varies according to a random walk, where

[0028] $\phi[k]-\phi[k-1]=\rho[I]$, where $\rho[I]$ is a zero-mean Gaussian random variable with variance $\sigma^2=2\pi\Delta\nu T_B$, where $\Delta\nu$ is the 3-dB line-width of the laser, and T_B is the baud-period of the signal;

[0029] d_m and θ_m , the temporal and phase delays associated with an interfering path, vary due to mechanical/thermal effects;

[0030] the additive noise $n[k]$ models other sources of noise in the channel;

[0031] due to independence of data symbols, $A[k]$, the amplitudes of the victims and interferers are jointly independent;

[0032] the γ_m models the attenuation of a reflected signal, originating from the return loss of the connectors at which the reflections occur;

[0033] The $\psi[m]$ are of the general form $\sum_{i=a}^b 2\theta_i$, for $a,b\in\{1,2,3,4,5\}$

[0034] Referring now to FIG. 5A, shown is a block diagram of an optical receiver including a MPI mitigation circuit **500** provided by an embodiment of invention. Block RX1 **501** represents any input signal processing that is performed prior to the MPI mitigation circuit **500**. Specific examples are given below. Block RX2 **510** represents receive signal processing that is performed after the MPI mitigation circuit **500**. Specific examples are given below. The MPI mitigation circuit **500** is implemented in a receiver connected to an optical signal path, such as exemplified in FIGS. 1 to 3.

[0035] The MPI-mitigation circuit **500** has an error generator **506** that estimates a PAM level of samples received from RX1 **501**, and generates a corresponding error signal. The error signal is filtered in low-pass filter **508** to produce estimates of the MPI. A compensation combiner **504** combines the estimates of the MPI with the samples received from RX1 **501**, optionally after a delay **502** that accounts for the time it takes to process the samples in the error generator **506** and the filter **508**.

[0036] FIG. 5B is a baud rate view of the MPI-mitigation circuit **500** of FIG. 5A. Input samples $r[k]$ are sliced in a slicer **522** that, for each sample, estimates a respective PAM level of the sample. A subtractor **524** (a specific example of error generator **506** of FIG. 5A), subtracts the sample from the respective estimated PAM level to generate a corresponding error sample. The error samples are filtered in lowpass filter **526** to produce estimates of MPI which are then subtracted from the input samples $r[k]$ with subtractor **528**.

[0037] There are many options for the low-pass filter. In some embodiments, the low-pass filter is a fixed block average component that determines an average of the error samples for a block of consecutive samples. The average thus determined is used as the estimate of MPI that is combined with each sample in the block of consecutive samples. In a specific example, the estimate of MPI is determined using a fixed 32-baud window according to:

$$\frac{1}{32}\sum_{k=0}^{31} \hat{\epsilon}[k]$$

[0038] The approach requires 31 additions per 32 bauds.

[0039] In some embodiments, the low-pass filter is a moving window average component that determines, for each sample, an average of the error samples for a respective block of error samples defined by a moving window, wherein the average is used as the estimate of MPI that is combined with the sample. In some embodiments, there is a unique window used for each sample. In other embodiments, the same window is used for a set of consecutive samples that is smaller than the size of the block of error samples. In a specific example, the estimate of MPI is determined using a sliding 32-baud window, with MPI mitigation common over 8 consecutive bauds according to:

$$\frac{1}{32}\sum_{k=0}^{31} \hat{\epsilon}[8i-12+k], i \in \{0, 1, 2, 3\}$$

[0040] The approach requires ≥ 40 additions per 32 bauds.

[0041] In some embodiments, a size of the block of consecutive samples (for fixed or moving window embodiments) is configured as a function of transmitter coherence.

[0042] In some embodiments, the compensation combiner **504** is a subtractor that combines the estimate of the component of multi-path interference with the sample to produce an interference-mitigated sample by subtracting the estimate from the sample to produce the interference-mitigated sample.

[0043] In some embodiments, the compensation combiner **504** is a level-dependent subtractor that produces a weighted estimate by multiplying the estimate of MPI output by the filter by a value proportional to a respective PAM level modulating the E-field estimated from the sample. This weighted estimate is then subtracted from the sample to produce the interference-mitigated sample. The PAM level modulating the E-field is to be distinguished from the output of a direct detector (for example slicer **522**), in that the PAM levels after direct detection are a function of power, and so are the square of the E-field amplitude.

[0044] As noted above, RX1 block **501** represents any input signal processing that is performed prior to the feed-forward MPI-mitigation circuit **500**. With reference to FIG. **6**, in a specific example, this includes at least a direct detection receiver such as a photodiode (PD) **600**, a transimpedance amplifier (TIA) **601** that amplifies the direct detection output, an analog to digital converter (ADC) **602** that performs analog to digital conversion on an output of the TIA to generate raw samples and an equalizer **604** that equalizes the raw samples to produce the plurality of samples. There may be different, or additional functionality in RX1 block **501**.

[0045] As noted above, RX2 block **510** represents any input signal processing that is performed after the feed-forward MPI-mitigation circuit **500**. In some embodiments, this includes a PAM decision slicer that performs PAM decision slicing for each interference-mitigated sample. There may be additional functionality in RX2 block **510**.

[0046] Another interference mitigation circuit provided by an embodiment of the invention will now be described with reference to FIG. **7**, which includes many components in common with FIG. **5A**. The circuit additionally includes an interference component estimator **702**, and a combiner **704** that receives an output of the MPI estimator **500** and one or more outputs of the interference component estimator **702**.

[0047] The interference component estimator **702** estimates at least one interference component by estimating a respective delay and respective amplitude for each interference component. Typically, the interference component estimator will estimate components due to electrical reflections. Because the electrical reflections typically occur over very short distances (on the order of tens of mm or less), they remain within a small number of bauds from the main signal. The combiner **705** combines the estimate of MPI and the estimated at least one electrical interference component **702** with the sample to produce interference mitigated samples that are passed on to RX2 block **510**.

[0048] With reference to FIG. **8**, another embodiment of the invention provides an optical module. The optical module has an optical IO (input/output) **802** and an electrical IO **804**. In respect of an optical signal received at the optical I/O, there is a photo-diode (PD) **810** for performing direct

detection to produce a direct detection output. The direct detection output is amplified in a TIA **812**. There is a PAM ASIC **806** configured to perform PAM demodulation on an output of the TIA **812** to produce a signal at the electrical IO **804**. The PAM ASIC includes an MPI mitigation circuit **804** that implements MPI mitigation in accordance with one of the embodiments described herein. The PAM ASIC may, for example, include the circuit of FIG. **6**.

[0049] In respect of signals received at the electrical IO **804**, the PAM ASIC is further configured to perform PAM modulation based on an incoming electrical signal. The optical module also has a laser plus modulator **808** that outputs an optical signal at the optical IO having a PAM modulated E-field based on the output of the PAM modulation.

[0050] Referring now to FIG. **9** shown is a block diagram of an optical communications system provided by an embodiment of the invention. The system includes a number of network elements **900,902** (only two shown, but there typically will be more). The network elements **902,904** may be switches, routers, servers for example. The network elements **902,904** are interconnected by optical paths that comprise optical fiber and optical interfaces. In the specific example illustrated, network elements **902,904** are interconnected by an optical path that includes optical fiber **908**, interface **914**, optical fiber **910**, interface **916**, and optical fiber **912**. The number of fibers and interfaces is implementation specific. In addition, at least one of the network elements includes an optical module having an MPI-mitigation circuit in accordance with one of the embodiments described herein. In the illustrated example, network elements **900,902** include respective optical modules **904,924** that include respective MPI mitigation circuits **906,926**. In some embodiments, the optical modules are in accordance with the example of FIG. **8**.

[0051] The specific operating frequencies, in terms of baud rate of the incoming signals, and the passband of the low-pass filter, are implementation specific. In some embodiments, the systems and methods described herein are applied for optical signals having a baud rate that is greater than 25 GBaud, and the MPI mitigation circuit performs low-pass filtering to remove MPI below frequencies of 100 MHz in some embodiments, and below 10 MHz in other embodiments.

[0052] FIG. **10** is flowchart of a method of processing a plurality of samples of an optical signal having a pulse amplitude modulated (PAM) E-field. In block **10-1**, for each sample, a respective PAM level is estimated. In block **10-2**, for each sample, the sample is subtracted from the respective PAM level to generate a corresponding error sample. In block **10-3**, the error samples are low-pass filtered to produce estimates of multi-path interference (MPI). In block **10-4**, for each sample, one of the estimates of MPI is combined with the sample to produce an interference-mitigated sample. Various examples of how these steps can be performed have been described above.

[0053] Numerous modifications and variations of the present disclosure are possible in light of the above teachings. It is therefore to be understood that within the scope of the appended claims, the disclosure may be practiced otherwise than as specifically described herein.

1. A circuit configured to receive a plurality of samples of an optical signal having a pulse amplitude modulated (PAM) E-field, the circuit comprising:

- a slicer configured to estimate a PAM level of a sample in the plurality of samples;
- a subtractor configured to generate an error sample by subtracting the sample from the estimated PAM level;
- a low-pass filter configured to filter the error sample for the sample and error samples for the other samples in the plurality of samples to produce estimates of multi-path interference (MPI); and
- a combiner configured to produce an interference-mitigated sample by combining one of the estimates of MPI with the sample.
2. The circuit of claim 1 wherein the subtractor is a first subtractor configured to subtract the sample from the estimated PAM level to generate a corresponding error sample.
3. The circuit of claim 1 wherein:
the subtractor is a first subtractor; and
the combiner is a second subtractor that is configured to combine one of the estimates of multi-path interference with the sample to produce an interference-mitigated sample by subtracting the estimate from the sample to produce the interference-mitigated sample.
4. The circuit of claim 1 wherein:
the subtractor is a first subtractor; and
the combiner is second, level-dependent subtractor that, for a given sample, is configured to combine one of the estimates of MPI with the sample to produce an interference-mitigated sample by producing a weighted estimate by multiplying the one of the estimates of MPI producing a weighted estimate by multiplying the one of the estimates of MPI with a value proportional to a respective PAM level modulating the E-field estimated from the sample, and subtracting the weighted estimate from the sample to produce the MPI-mitigated sample.
5. The circuit of claim 4 wherein the first subtractor is configured to subtract the sample from the estimated PAM level to generate a corresponding error sample.
6. The circuit of claim 1 wherein the low-pass filter comprises:
a fixed block average component configured to determine an average of the error samples for a block of samples; wherein the average is used as the estimate of MPI that is combined with each sample in the block of samples.
7. The circuit of claim 6 wherein the block of samples comprises consecutive samples.
8. The circuit of claim 7 wherein a size of the block of consecutive samples is configured as a function of transmitter coherence.
9. The circuit of claim 1 wherein the low-pass filter comprises:
a moving window average component configured to determine, for each sample, an average of the error samples for a respective block of error samples defined by a moving window, wherein the average is used as the estimate of MPI that is combined with the sample.
10. The circuit of claim 9 wherein the block of samples comprises consecutive samples.
11. The circuit of claim 10 wherein a size of the block of consecutive samples is configured as a function of transmitter coherence.
12. The circuit of claim 1 operating at a baud rate of greater than 25 GBaud, in which the low-pass filter operates to filter frequencies below 100 MHz.
13. The circuit of claim 1 operating at a baud rate of greater than 25 GBaud, in which the low-pass filter operates to filter frequencies below 10 MHz.
14. The circuit of claim 1 further comprising:
a delay element configured to delay the sample before combining to account for a delay in determining the one of the estimates of MPI.
15. The circuit of claim 1 further comprising:
a direct detection receiver configured to directly detect the optical signal to produce a direct detection output.
16. The circuit of claim 15 further comprising:
a converter configured to perform analog to digital conversion on the direct detection output to generate raw samples.
17. The circuit of claim 16 further comprising:
an equalizer configured to equalize the raw samples to produce the plurality of samples.
18. The circuit of claim 17 further comprising:
a PAM decision slicer configured to perform PAM decision slicing for each interference-mitigated sample.
19. The circuit of claim 1 further comprising:
an interference component estimator configured to estimate at least one interference component by estimating a respective delay and respective amplitude for each interference component;
wherein for each sample, the combiner is configured to combine the estimate of MPI and the estimated at least one electrical interference component with the sample;
a PAM decision slicer configured to perform PAM decision slicing for each interference-mitigated sample.
20. The circuit of claim 1 further comprising:
a PAM decision slicer configured to perform PAM decision slicing for each interference-mitigated sample.

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